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Docket No.: 067161-0068

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Jun SUMINO, et al.

Application No.: 10/617,667

Filed: July 14, 2003

For: SEMICONDUCTOR DEVICE

Customer Number: 20277

Confirmation Number: 4737

Group Art Unit: 2822

Examiner: PRENTY, MARK V.

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of a Final Rejection or Notice of Allowance, but before payment of the Issue Fee.

REQUEST TO CONSIDER REFERENCES AFTER CLOSE OF PROSECUTION AND  
BEFORE PAYMENT OF ISSUE FEE

The undersigned hereby requests consideration and entry of this Information Disclosure Statement and accompanying references under 37 CFR 1.97(d).

Please charge the processing fee under 1.17(p) of \$180.00 to Deposit Account 500417.

11/09/2005 HALI11 00000056 500417 10617667

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CERTIFICATION PARAGRAPH

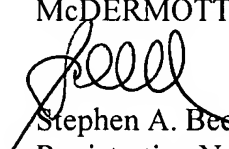
The undersigned certifies that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement as described in 37 CFR 1.97(e)(1).

Each reference was cited in a corresponding foreign application search report or office action and its relevance discussed therein. A copy of the foreign search report or office action, together with an English language version thereof, is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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**Please recognize our Customer No. 20277  
as our correspondence address.**

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. <b>067161-0068</b>		SERIAL NO. <b>10/617,667</b>			
						APPLICANT <b>Jun SUMINO, et al.</b>					
(PTO-1449)						FILING DATE <b>July 14, 2003</b>		GROUP <b>2822</b>			
U.S. PATENT DOCUMENTS											
EXAMINER'S INITIALS		CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)		Publication Date MM-DD-YYYY		Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
			US	6,566,224 B1	05-20-2003	Chang et al.					
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FOREIGN PATENT DOCUMENTS											
EXAMINER'S INITIALS		CITE NO.	Foreign Patent Document Country Codes - Number + - Kind Codes (if known)		Publication Date MM-DD-YYYY		Name of Patentee or Applicant of Cited Document		Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)											
EXAMINER'S INITIALS		CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
			Korean Office Action dated September 23, 2005 in corresponding Korean Application No. 10-2003-0066126								
			K. SHIMIZU, et al. "A Novel High-Density 5F <sup>2</sup> NAND STI Cell Technology Suitable for 256Mbit and 1Gbit Flash Memories," International Electron Device Meeting, 1997								
			Surya BHATTACHARYA, "Improved Performance and Reliability of Split Gate Source-Side Injected Flash Memory Cells," International Electron Device Meeting, 1995								
EXAMINER						DATE CONSIDERED					

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.